

EL979953650

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2445	SERIAL NO. Filed Herewith 10/765,699
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.	
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U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TL	AA	6,649,503	1/18/03	Kim et al.			
	AB	6,635,556	10/21/03	Goo et al.			
	AC	6,596,607	7/22/03	Ahn			
	AD	6,489,252	12/3/2002	Goo et al.			
	AE	6,479,405	11/12/2002	Lee et al.			
	AF	6,432,843	8/13/02	Kim et al.			
	AG	6,399,438	6/4/02	Saito et al.			
	AH	6,184,143	2/6/01	Ohashi et al.			

FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AI						
	AJ						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	AK		
	AL		
	AM		
	AN		
	AO		

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2445	SERIAL NO. Filed Herewith 10/765,698
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Microa Technology, Inc.	
				FILING DATE Filed Herewith	GROUP Unknown 2818

U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
π <div style="border-left: 1px solid black; height: 100px; margin: 0 auto; width: 20px;"></div>	AA	6,258,649	7/10/01	Nakamura et al.			
	AB	6,187,662	2/13/01	Usami et al.			
	AC	6,215,144	4/10/01	Saito et al.			
	AD	6,235,620	3/22/01	Saito et al.			
	AE	6,261,883	7/17/01	Koubuchi et al.			
	AF	5,169,491	12/8/92	Doan			
	AG	5,618,381	4/8/97	Doan et al.			
	AH						

FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AI						
	AJ						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
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